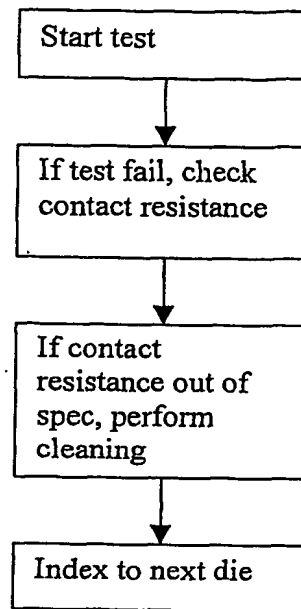


**Figure 1**

**Figure 2**

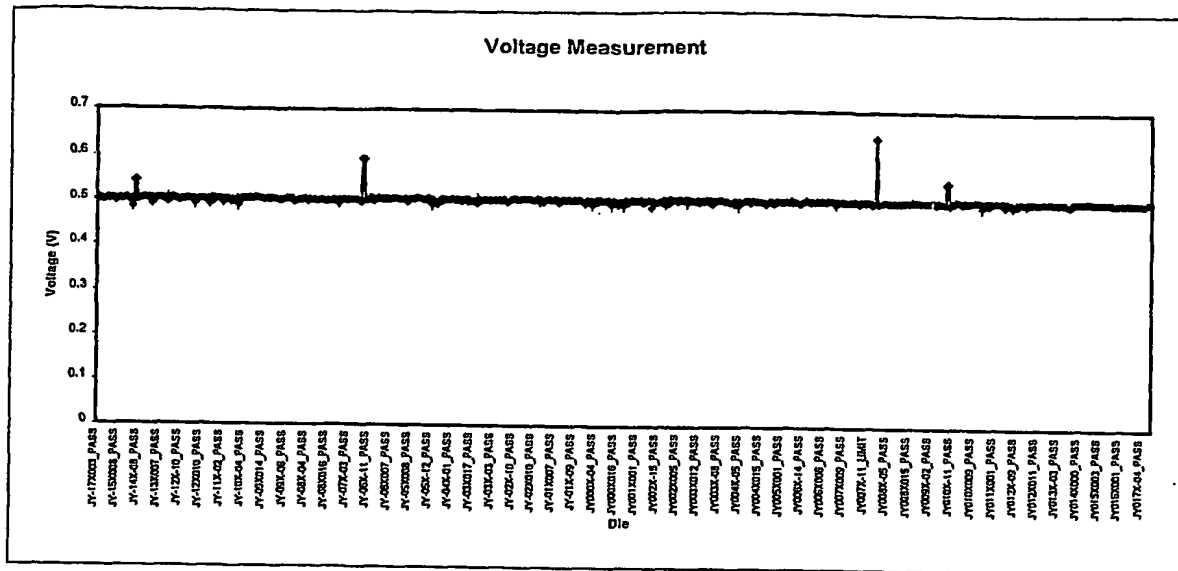


Figure 3

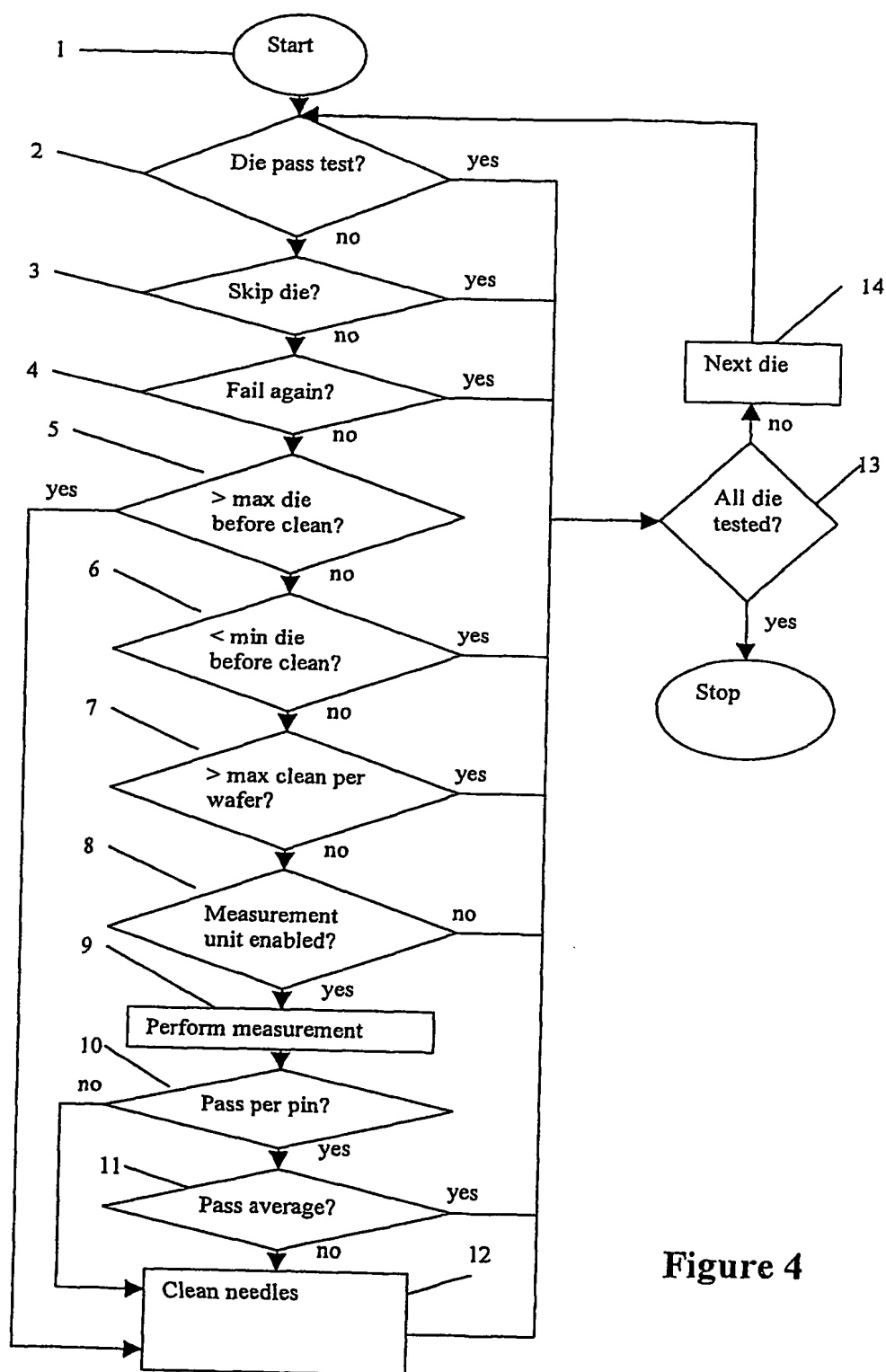


Figure 4

s16388.1\_06.20021001011407

Top

Device:	TMF105	Tester:	D342X
Lot ID:	s16388.1	Board Num:	1
Wafer ID:	06	Touchdown:	1072
Operator ID:	1058	Probe Card:	3
Test Mode:	0	Indexing:	987
Timestamp:	20021001011407	Good Die:	898
		Recovery:	3
		RRR:	0.33

Bin to Bin Recovery	Count	%	Top 10 CRC Fail Pins	Count	%
IDD_FAIL(7) -> SCAN_SP_FAIL(16)	1	0.11	xo(73)	2	40.00
BIST_NOM_FAIL(8) -> GOOD(1)	1	0.11	pll0(11)	2	40.00
OPEN_FAIL(2) -> GOOD(1)	1	0.11	gdk1(2)	2	40.00
AMCLK(19) -> GOOD(1)	1	0.11	gdk(1)	2	40.00
FAIL -> GOOD	3	0.34			

Figure 5